

A	Application/Control No.	Applicant(s)/Patent und Reexamination	ler
1	0/810,258	HU ET AL.	
E	xaminer	Art Unit	
ر. ا	a-Na Hines	1645	

	SEARCHED					
Class	Subclass	Date	Examiner			
422	85898 85898	2/14/2006	JAH			
	104					
435	10 7.1 287.2					
	287.8 287.9 288.3 288.6					
	280.0					

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
west, derwent, commerical databases, caplus, eplus, japio, scisearch, biotechno, biosis	2/14/2006	JAH		
consulted primary in 1641				
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